

Comparative Measurements of Secondary Standards for Paint Layers on Plastic and Glass Substrates

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Abstract

Systematic measurements have been carried out for Secondary Painted Layer Standards on plastic and glass substrates. Final results for measurement of lead concentration for 20-60- μm thick paint samples show good agreement between High Definition X-Ray Fluorescence (HD XRF), Atomic Absorption Spectrometry (AAS) and Inductively Coupled Plasma Optical Emission Spectrometry (ICP-OES) analytical techniques. Measurements with a NITON Handheld XRF analyzer performed on the same secondary paint standards were found to be inadequate.